SN74LVC821A供应商

SN74LVC821A 10-BIT BUS-INTERFACE FLIP-FLOP WITH 3-STATE OUTPUTS

SCAS304F - MARCH 1993 - REVISED JUNE 1998

 EPIC[™] (Enhanced-Performance Implanted CMOS) Submicron Process 	DB, DW, OR PW PACKAGE (TOP VIEW)				
 Typical V_{OLP} (Output Ground Bounce) < 0.8 V at V_{CC} = 3.3 V, T_A = 25°C 	$\frac{\overline{OE}}{1} \begin{bmatrix} 1 & 24 \\ 24 \end{bmatrix} V_{CC}$				
 Typical V_{OHV} (Output V_{OH} Undershoot) > 2 V at V_{CC} = 3.3 V, T_A = 25°C 	2D [] 3 22]] 2Q 3D [] 4 21]] 3Q				
 Supports Mixed-Mode Signal Operation on All Ports (5-V Input/Output Voltage With 2.2 V(v = x) 	4D 5 20 4Q 5D 6 19 5Q 6D 7 18 6Q				
 3.3-V V_{CC}) Power Off Disables Outputs, Permitting Live Insertion 	7D [8 17] 7Q 8D [9 16] 8Q				
 ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015 	9D [10 15] 9Q 10D [11 14] 10Q GND [12 13] CLK				
 Latch-Up Performance Exceeds 250 mA Per JESD 17 					
Backage Options Include Blastic					

 Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages

description

This 10-bit bus-interface flip-flop is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74LVC821A features 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing wider buffer registers, I/O ports, bidirectional bus drivers with parity, and working registers.

The ten flip-flops are edge-triggered D-type flip-flops. On the positive transition of the clock (CLK) input, the device provides true data at the Q outputs.

A buffered output-enable (\overline{OE}) input can be used to place the ten outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

OE does not affect the internal operations of the latch. Previously stored data can be retained or new data can be entered while the outputs are in the high-impedance state.

Inputs can be driven from either 3.3-V or 5-V devices. This feature allows the use of these devices as translators in a mixed 3.3-V/5-V system environment.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74LVC821A is characterized for operation from –40°C to 85°C.



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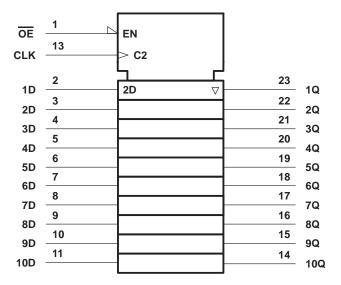
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FUNCTION TABLE £111. - 41

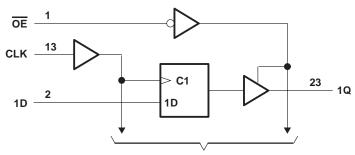
(each flip-flop)									
	INPUTS	OUTPUT							
OE	CLK	D	Q						
L	\uparrow	Н	Н						
L	\uparrow	L	L						
L	H or L	Х	Q ₀						
Н	Х	Х	Z						

logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



To Nine Other Channels



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC} Input voltage range, V _I (see Note 1)	
Voltage range applied to any output in the high-impedance or power (see Note 1)	r-off state, V _O
Voltage range applied to any output in the high or low state, V_O	
(see Notes 1 and 2)	-0.5 V to V _{CC} + 0.5 V
Input clamp current, I_{IK} (V _I < 0)	–50 mA
Output clamp current, I _{OK} (V _O < 0)	
Continuous output current, I _O	
Continuous current through V _{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DB package	104°C/W
PW package	120°C/W
Storage temperature range, T _{stg}	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The value of V_{CC} is provided in the recommended operating conditions table.

3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT	
Vaa	Supply voltage	Operating	1.65	3.6	V	
VCC	Supply voltage	Data retention only	1.5		v	
		V _{CC} = 1.65 V to 1.95 V	$0.65 \times V_{CC}$			
VIH	High-level input voltage	V _{CC} = 2.3 V to 2.7 V	1.7		V	
		V _{CC} = 2.7 V to 3.6 V	2			
VIL		V _{CC} = 1.65 V to 1.95 V		$0.35 \times V_{CC}$		
	Low-level input voltage	V_{CC} = 2.3 V to 2.7 V		0.7	V	
		V _{CC} = 2.7 V to 3.6 V		0.8		
VI	Input voltage	•	0	5.5	V	
VO	Output voltage	High or low state	0	VCC		
		3 state	0	5.5	V	
		V _{CC} = 1.65 V		-4		
1	High-level output current	V _{CC} = 2.3 V		-8	mA	
ЮН		V _{CC} = 2.7 V		-12		
		V _{CC} = 3 V		-24		
		V _{CC} = 1.65 V		4		
le.		V _{CC} = 2.3 V		8	A	
IOL	Low-level output current	V _{CC} = 2.7 V		12	mA	
		V _{CC} = 3 V		24		
$\Delta t/\Delta v$	Input transition rise or fall rate	-	0	10	ns/V	
TA	Operating free-air temperature		-40	85	°C	

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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electrical chara	acteristics ove	r recommended	operating	free-air	temperature	range	(unless
otherwise note	d)				-	•	•

PA	RAMETER	TEST CO	ONDITIONS	Vcc	MIN	TYP†	MAX	UNIT	
		I _{OH} = -100 μA		1.65 V to 3.6 V	V _{CC} -0.2				
VOH	$I_{OH} = -4 \text{ mA}$	1.65 V	1.2						
	I _{OH} =8 mA		2.3 V	1.7			V		
VОН		10		2.7 V	2.2			v	
		I _{OH} = -12 mA	3 V	2.4					
	I _{OH} = -24 mA		3 V	2.2					
		I _{OL} = 100 μA		1.65 V to 3.6 V			0.2		
		I _{OL} = 4 mA	1.65 V			0.45			
VOL	IOL = 8 mA	2.3 V			0.7	V			
		I _{OL} = 12 mA	2.7 V			0.4			
		I _{OL} = 24 mA	3 V			0.55			
II		V _I = 0 to 5.5 V		3.6 V			±5	μA	
loff		V _I or V _O = 5.5 V		0			±10	μA	
Ioz		V _O = 0 to 5.5 V		3.6 V			±10	μA	
		V _I = V _{CC} or GND					10		
ICC		$3.6 V \le V_I \le 5.5 V^{\ddagger}$	IO = 0	3.6 V			10	μA	
∆ICC		One input at V _{CC} – 0.6 V,	Other inputs at V _{CC} or GND	2.7 V to 3.6 V			500	μA	
<u>C.</u>	Control inputs			2.2.1/		5		~ F	
Ci	Data inputs	$V_{I} = V_{CC}$ or GND		3.3 V		4		рF	
Co		$V_{O} = V_{CC}$ or GND		3.3 V		7		pF	

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C. [‡] This applies in the disabled state only.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = ± 0.1	1.8 V 5 V	V _{CC} = ± 0.2	2.5 V 2 V	V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
fclock	Clock frequency		§		§		150		150	MHz
tw	Pulse duration, CLK high or low	§		§		3.3		3.3		ns
t _{su}	Setup time, data before CLK	§		§		1.9		1.9		ns
t _h	Hold time, data after CLK	§		§		1.5		1.5		ns

§ This information was not available at the time of publication.



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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = ± 0.1		V _{CC} = ± 0.2	2.5 V 2 V	V _{CC} =	2.7 V	= ۷ _{CC} ± 0.3	3.3 V 3 V	UNIT
		(001101)	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		†		150		150		MHz
^t pd	CLK	Q	†	†	†	†		8.5	2.2	7.3	ns
t _{en}	OE	Q	†	†	†	†		8.8	1.3	7.6	ns
^t dis	OE	Q	†	†	†	†		6.8	1.6	6.2	ns
^t sk(o) [‡]										1	ns

[†]This information was not available at the time of publication.

[‡] Skew between any two outputs of the same package switching in the same direction

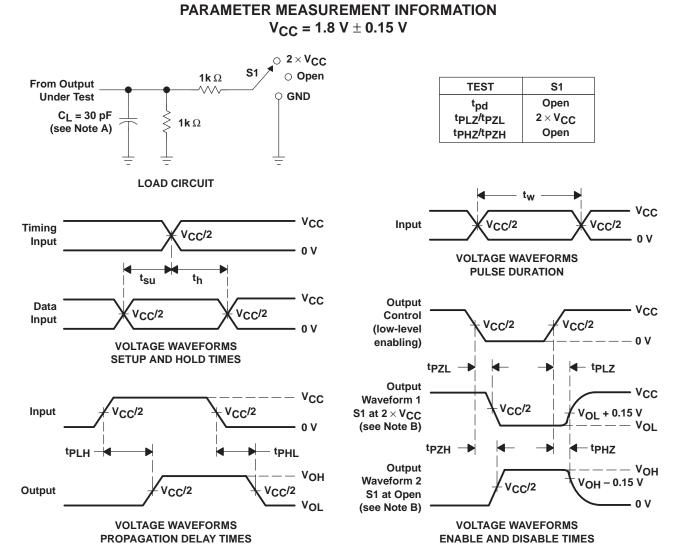
operating characteristics, $T_A = 25^{\circ}C$

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V ± 0.15 V	$\begin{array}{c} \text{V}_{\text{CC}} = 2.5 \text{ V} \\ \pm 0.2 \text{ V} \end{array}$	V _{CC} = 3.3 V ± 0.3 V	UNIT	
				TYP	TYP	TYP		
Cpd	Power dissipation capacitance	Outputs enabled	f = 10 MHz	†	†	65	рF	
Сра	per flip-flop	Outputs disabled		†	†	48	рг	

[†] This information was not available at the time of publication.



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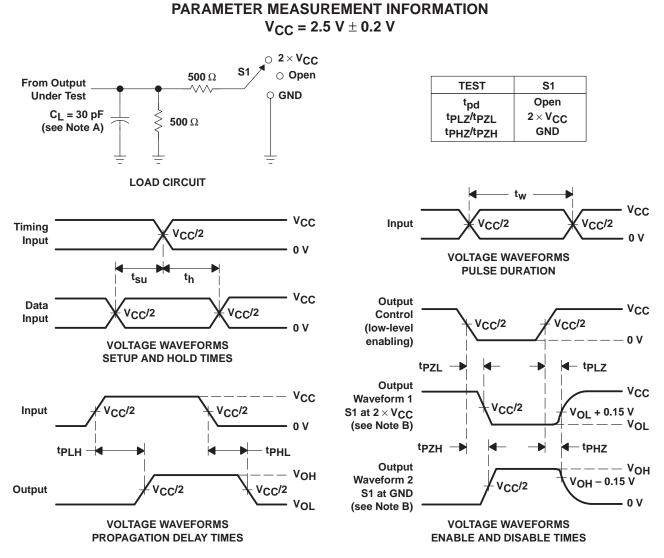


- NOTES: A. CL includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control. C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f \leq 2 ns, t_f \leq 2 ns.

 - D. The outputs are measured one at a time with one transition per measurement.
 - E. tPLZ and tPHZ are the same as tdis.
 - F. tp71 and tp7H are the same as ten.
 - G. tpi H and tpHi are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms





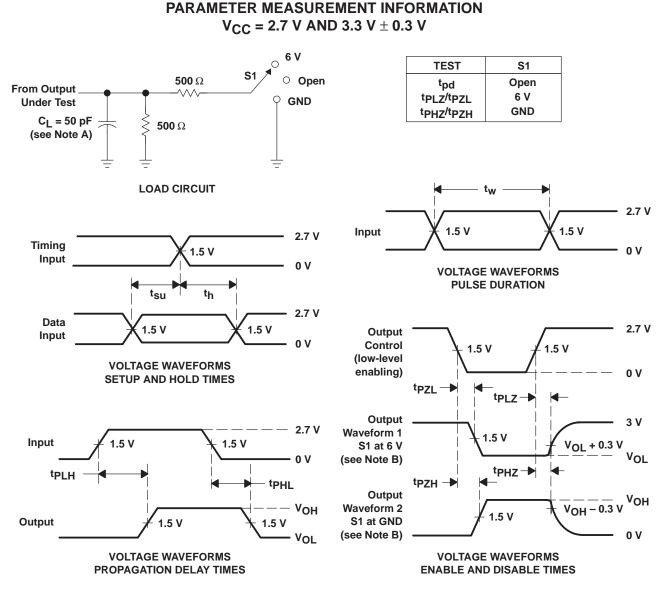
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 - D. The outputs are measured one at a time with one transition per measurement.
 - D. The outputs are measured one at a time with one tr
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. tPLH and tPHL are the same as tpd.

Figure 2. Load Circuit and Voltage Waveforms



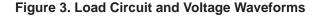
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NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_r \leq 2.5 ns, t_f \leq 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tPLZ and tPHZ are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tPLH and tPHL are the same as tpd.





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